Title (en)
DESIRED WAVE/INTERFERENCE POWER RATIO MEASURING CIRCUIT AND DESIRED WAVE/INTERFERENCE POWER RATIO MEASURING METHOD

Title (de)
SCHALTUNG UND VERFAHREN ZUR MESSUNG DES VERHÄLTNISSES VON GEWÜNSCHTER WELLENLEISTUNG ZUR STÖRLEISTUNG

Title (fr)
CIRCUIT ET METHODE DE MESURE DU RAPPORT ONDE DESIREE/PUISSANCE DES PARASITES

Publication
EP 1239615 A1 20020911 (EN)

Application
EP 01981046 A 20011109

Priority
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• JP 2000341648 A 20001109

Abstract (en)
A bias error in a low SIR area is corrected by subtracting a value of an interference signal power multiplied by a first correction coefficient which has been determined from an SIR characteristic diagram obtained in advance from a desired signal power to remove an interference signal component included in the desired signal power. Also, a bias error in a high SIR area is corrected by subtracting a value of a desired signal power multiplied by a second correction coefficient which has been determined from the SIR characteristic diagram obtained in advance from an interference signal power to remove a desired signal component included in the interference signal power. <IMAGE>

IPC 1-7
H04B 17/00

IPC 8 full level
G01R 29/00 (2006.01); **G01R 29/26** (2006.01); **H04B 7/26** (2006.01); **H04B 17/00** (2015.01); **H04B 17/336** (2015.01); **H04W 24/00** (2009.01); **H04W 88/00** (2009.01)

CPC (source: EP US)
H04B 17/21 (2015.01 - EP US); **H04B 17/336** (2015.01 - EP US)

Citation (search report)
See references of WO 0239626A1

Cited by
EP1639837A4; EP1859548A4; EP2156599A4; WO2005006779A2; US8559895B2; WO2009154590A3; WO2006105297A3; WO2005125066A1; WO2006088259A1; US7558576B2; US8503328B2; US8599972B2

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